In the Specification:

Please amend the abstract of the disclosure starting at page 18, line 4 as follows:

A method and apparatus are provided for detecting degradation, such as, array degradation and logic degradation, in integrated circuits (ICs) including~~, for example,~~ application specific integrated circuits (ASICs). A monitor built-in self-test (MBIST) engine ~~is provided. At~~ <u>coupled to at</u> least one monitor element ~~is coupled to the MBIST engine and~~ <u>that</u> is defined by predefined circuit elements in the integrated circuit. The MBIST engine is used for controlling operation of at least one monitor element for communicating with monitor bits to identify degradation of signal, timing and voltage margins.